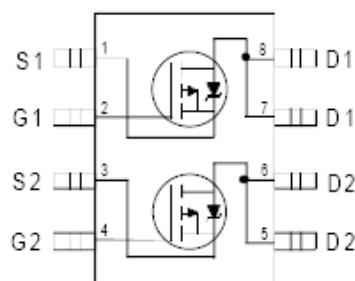
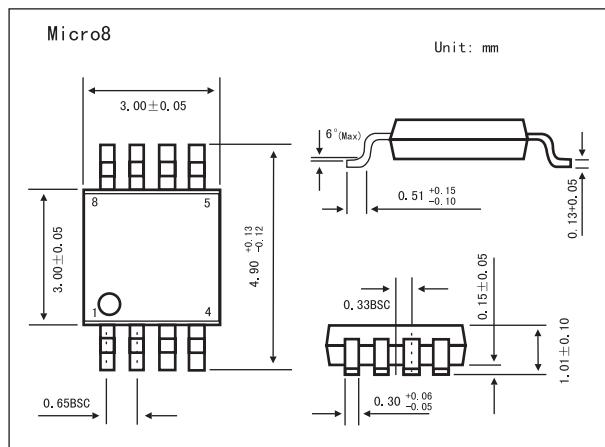


HEXFET® Power MOSFET

KRF7504

■ Features

- Generation V Technology
- Ultra Low On-Resistance
- Dual P-Channel MOSFET
- Very Small SOIC Package
- Low Profile (<1.1mm)
- Available in Tape & Reel
- Fast Switching



■ Absolute Maximum Ratings Ta = 25°C

| Parameter | Symbol | Rating | Unit |
|---|----------|--------------|--------|
| Continuous Drain Current, Vgs @ -4.5V @ TA = 25°C | Id | -1.7 | A |
| Continuous Drain Current, Vgs @ -4.5V @ TA = 70°C | Id | -1.4 | |
| Pulsed Drain Current *1 | Idm | -9.6 | |
| Power Dissipation *2 @TA= 25°C | Pd | 1.25 | W |
| Linear Derating Factor | | 10 | m W/°C |
| Gate-to-Source Voltage | Vgs | ±12 | V |
| Peak Diode Recovery dv/dt *3 | dv/dt | -5.0 | V/ns |
| Junction and Storage Temperature Range | Tj, Tstg | -55 to + 150 | °C |
| Maximum Junction-to-Ambient *2 | Rθ JA | 100 | °C/W |

*1 Repetitive rating; pulse width limited by max. junction temperature.

*2 Surface mounted on FR-4 board, t ≤ 10sec

*3 Id ≤ -1.2A, di/dt ≤ 100A/μ s, Vdd ≤ V(BR)DSS, TJ ≤ 150°C

KRF7504■ Electrical Characteristics $T_a = 25^\circ\text{C}$

| Parameter | Symbol | Testconditons | Min | Typ | Max | Unit |
|--|---|---|------|--------|-------|---------------------------|
| Drain-to-Source Breakdown Voltage | $V_{(\text{BR})\text{DSS}}$ | $V_{\text{GS}} = 0\text{V}, I_D = -250\ \mu\text{A}$ | -20 | | | V |
| Breakdown Voltage Temp. Coefficient | $\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$ | $I_D = -1\text{mA}$, Reference to 25°C | | -0.012 | | $\text{V}/^\circ\text{C}$ |
| Static Drain-to-Source On-Resistance | $R_{\text{DS}(\text{on})}$ | $V_{\text{GS}} = -4.5\text{V}, I_D = -1.2\text{A}^*$ | | 0.27 | | Ω |
| | | $V_{\text{GS}} = -2.7\text{V}, I_D = -0.60\text{A}^*$ | | 0.40 | | |
| Gate Threshold Voltage | $V_{\text{GS}(\text{th})}$ | $V_{\text{DS}} = V_{\text{GS}}, I_D = -250\ \mu\text{A}$ | -0.7 | | | V |
| Forward Transconductance | g_{fs} | $V_{\text{DS}} = -10\text{V}, I_D = -0.60\text{A}^*$ | 1.3 | | | S |
| Drain-to-Source Leakage Current | I_{DSS} | $V_{\text{DS}} = -16\text{V}, V_{\text{GS}} = 0\text{V}$ | | | -1.0 | μA |
| | | $V_{\text{DS}} = -16\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$ | | | -25 | |
| Gate-to-Source Forward Leakage | I_{GSS} | $V_{\text{GS}} = -12\text{V}$ | | | -100 | nA |
| Gate-to-Source Reverse Leakage | | $V_{\text{GS}} = 12\text{V}$ | | | 100 | |
| Total Gate Charge | Q_g | $I_D = -1.2\text{A}$ | | 5.4 | 8.2 | nC |
| Gate-to-Source Charge | Q_{gs} | $V_{\text{DS}} = -16\text{V}$ | | 0.96 | 1.4 | |
| Gate-to-Drain ("Miller") Charge | Q_{gd} | $V_{\text{GS}} = -4.5\text{V}$ | | 2.4 | 3.6 | |
| Turn-On Delay Time | $t_{\text{d}(\text{on})}$ | $V_{\text{DD}} = -10\text{V}$ | | 9.1 | | ns |
| Rise Time | t_r | $I_D = -1.2\text{A}$ | | 35 | | |
| Turn-Off Delay Time | $t_{\text{d}(\text{off})}$ | $R_D = 8.3\ \Omega$ | | 38 | | |
| Fall Time | t_f | $R_g = 6\ \Omega$ | | 43 | | |
| Input Capacitance | C_{iss} | $V_{\text{GS}} = 0\text{V}$ | | 240 | | pF |
| Output Capacitance | C_{oss} | $V_{\text{DS}} = -15\text{V}$ | | 130 | | |
| Reverse Transfer Capacitance | C_{rss} | $f = 1.0\text{MHz}$ | | 64 | | |
| Continuous Source Current (Body Diode) | I_s | MOSFET symbol showing the integral reverse p-n junction diode. | | | -1.25 | A |
| Pulsed Source Current (Body Diode) *2 | I_{SM} | | | | -9.6 | |
| Diode Forward Voltage | V_{SD} | $T_J = 25^\circ\text{C}, I_s = -1.2\text{A}, V_{\text{GS}} = 0\text{V}^*$ | | | -1.2 | V |
| Reverse Recovery Time | t_{rr} | $T_J = 25^\circ\text{C}, I_F = -1.2\text{A}$ | | 52 | 78 | ns |
| Reverse RecoveryCharge | Q_{rr} | $dI/dt = 100\text{A}/\mu\text{s}^*$ | | 63 | 95 | nC |
| Forward Turn-On Time | t_{on} | Intrinsic turn-on time is negligible (turn-on is dominated by L_s+L_d) | | | | |

*1 Pulse width $\leq 300\ \mu\text{s}$; duty cycle $\leq 2\%$.

*2 Repetitive rating; pulse width limited by max. junction temperature.

